

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICESUPPLEMENTAL  
INFORMATION DISCLOSURE STATEMENT  
(Use several sheets if necessary)ATTY. DOCKET NO.  
130109.484APPLICATION NO.  
10/666,919

APPLICANTS

Janusz Blaszczyk et al.

FILING DATE

September 18, 2003

GROUP ART UNIT

1745

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
JC	AK	1 471 324	04/21/77	GB		
JC	AL	WO 2004/038838 A2	05/06/04	WIPO		
	AM					
	AN					
	AO					

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AP	
	AQ	
	AR	

EXAMINER

/Jonathan Crepeau/

DATE CONSIDERED

10/04/2006

\* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

FORM PTO-1449 (REV. 7-99)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 130109.484	APPLICATION NO. 10/666,919
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## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JC	AA	3,462,308	08/19/69	Winters	136	36	
	AB	3,982,961	09/28/76	Grasso	429	34	
	AC	4,769,297	09/06/88	Reiser et al.	429	17	
	AD	5,082,752	01/21/92	Koga et al.	429	20	
	AE	5,169,730	12/08/92	Reichner et al.	429	20	
	AF	5,441,821	08/15/95	Merritt et al.	429	17	
	AG	6,013,385	01/11/00	DuBose	429	17	
	AH	2002/022171	02/21/02	Saito et al.	429	34	
	AI	2002/0022172	02/21/02	Sahoda et al.	429	34	
	AJ	2002/0041985	04/11/02	Shimanuki et al.	429	17	
	AK	2002/0136942	09/26/02	Kashiwagi	429	34	
	AL	2003/0008185	01/09/03	Sugino et al.	429	13	
	AM	2003/0012989	01/16/03	Ueda et al.	429	22	
	AN	2003/0096145	05/22/03	Sugawara et al.	429	22	
	AO	2003/0148167	08/07/03	Sugawara et al.	429	34	
JC	AP	2003/0180599	09/25/03	Kamihara	429	34	

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
JC	AQ	2001-266922	09/28/01	JP (+ Abstract in English)		
JC	AR	WO 03/043114 A2	05/22/03	WIPO		

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AS	
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EXAMINER /Jonathan Crepeau/	DATE CONSIDERED 10/04/2006
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